

# SN55LVDS32-SP

ZHCS771 - MARCH 2012

J OR W PACKAGE

(TOP VIEW)

1B 👖

1A 🛛 2

1Y 🛛 3

GLI 4

5

6

7

8

2Y 🛙

2A 🌡

2B Ц

GND

16 V<sub>CC</sub>

15 4B

140 4A

13 4Y

12 G

11 J 3Y

10 3A

9

3B

# 高速差分线路接收器

#### 特性

- 符合 QML-V, SMD 5962-97621
  由一个单 3.3V 电源供电运行
- 设计用于信号传输速率高达 100Mbps 的应用
- 最大差分输入阀值为 ±100mV
- 典型传播延迟时间为 2.1ns
- 在最大数据速率下每个接收器的功率耗散典型值为 60mW
- 总线-端子静电放电 (ESD) 保护超过 8kV
- 低压 TTL(LVTTL) 逻辑输入电平
- 开电路故障安全
- 针对有冗余需求的太空和高可靠性应用的冷备用

# 说明

SN55LVDS32 是一款差分线路驱动器,此驱动器执行低压差分信号传输 (LVDS) 的电气特性。 这个信号传输技术 降低了 5V 差分标准电平(例如 EIA/TIA-422B)的输出电压电平,从而减少了功耗、增加了开关速度、并可实现在 3.3V 电源轨供电下的运行。 四个差分接收器中的任何一个在输入共模电压范围内提供具有 ±100mV 差分输入电压 的有效逻辑输出状态。 此输入共模电压范围允许两个 LVDS 节点间 1V 的接地电势差。

这些器件和信号传输技术用于接近 100Ω 的受控阻抗介质上的点到点和多支路(一个驱动器和多个接收器)的数据 传输应用。此传输介质可以是印刷电路板走线、底板、或者电缆。数据传输的最终速率和距离取决于介质的衰减特 性和环境的噪声耦合。

SN55LVDS32 额定运行温度介于 -55℃ 至 125℃ 之间。



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

# SN55LVDS32-SP



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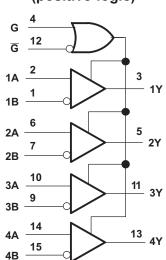
These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

#### **ORDERING INFORMATION**<sup>(1)</sup>

T <sub>A</sub>	PACKAGE <sup>(2)</sup>	ORDERABLE PART NUMBER	TOP-SIDE MARKING
5500 10 40500	CDIP - J	5962-9762201VEA	5962-9762201VEA
–55°C to 125°C	CFP - W	5962-9762201VFA	5962-9762201VFA

(1) For the most current package and ordering information, see the Package Option Addendum at the end of this document, or see the TI website at www.ti.com.

(2) Package drawings, standard packing quantities, thermal data, symbolization, and PCB design guidelines are available at www.ti.com/sc/package.



# SN55LVDS32 logic diagram (positive logic)



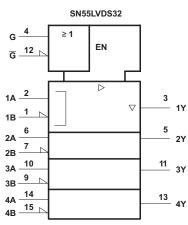
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SN55LVDS32								
DIFFERENTIAL INPUT	ENA	BLES	OUTPUT					
А, В	G	G	Y					
\/100 m\/	Н	Х	Н					
V <sub>ID</sub> ≥ 100 mV	Х	L	Н					
100  m (-1) (-5100  m)	н	Х	?					
−100 mV < V <sub>ID</sub> ≤ 100 mV	Х	L	?					
1/(-100 m)/(-100 m)	Н	х	L					
$V_{ID} \le -100 \text{ mV}$	Х	L	L					
Х	L	Н	Z					
Onen	н	Х	Н					
Open	Х	L	Н					

### Table 1. FUNCTION TABLE<sup>(1)</sup>

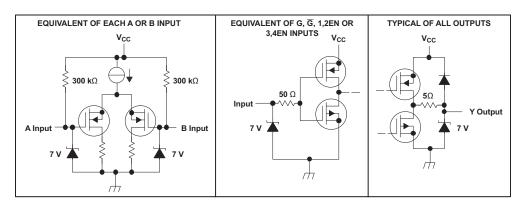
(1) H = high level, L = low level, X = irrelevant, Z = high impedance (off), ? = indeterminate



#### logic symbol<sup>†</sup>

 $^\dagger$  This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

### EQUIVALENT INPUT AND OUTPUT SCHEMATIC DIAGRAMS



# ZHCS771 - MARCH 2012 ABSOLUTE MAXIMUM RATINGS<sup>(1)</sup>

over operating free-air temperature range (unless otherwise noted)

			UNIT
$V_{CC}$	Supply voltage range <sup>(2)</sup>		–0.5 V to 4 V
VI	Input voltage range	Enables and output	–0.5 V to V <sub>CC</sub> + 0.5 V
		A or B	–0.5 V to 4 V
	Continuous total power dissipation	See Dissipation Rating Table	
	Lead temperature 1,6 mm (1/16 inch) from case for 10 se	260°C	
T <sub>stg</sub>	Storage temperature range	–65°C to 150°C	

(1) Stresses beyond those listed under absolute maximum ratings may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under recommended operating conditions is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

(2) All voltages, except differential I/O bus voltages, are with respect to the network ground terminal.

#### **DISSIPATION RATING TABLE**

PACKAGE	T <sub>A</sub> ≤ 25°C POWER RATING	DERATING FACTOR <sup>(1)</sup> ABOVE T <sub>A</sub> = 25°C	T <sub>A</sub> = 70°C POWER RATING	T <sub>A</sub> = 85°C POWER RATING	T <sub>A</sub> = 125°C POWER RATING
J	1375 mW	11 mW/°C	880 mW	715 mW	275 mW
W	1000 mW	8 mW/°C	640 mW	520 mW	200 mW

(1) This is the inverse of the junction-to-ambient thermal resistance when board-mounted and with no air flow.

#### **RECOMMENDED OPERATING CONDITIONS**

			MIN	NOM	MAX	UNIT
V <sub>CC</sub>	Supply voltage		3	3.3	3.6	V
VIH	High-level input voltage G, G, 1,2EN, or 3,4EN		2			V
VIL	Low-level input voltage	G, G, 1,2EN, or 3,4EN			0.8	V
$ V_{ID} $	Magnitude of differential inpu	t voltage	0.1		0.6	V
VIC	Common-mode input voltage (see Figure 1)		V <sub>ID</sub>  /2		2.4 -  V <sub>ID</sub>  /2	V
					V <sub>CC</sub> - 0.8	v
T <sub>A</sub>	Operating free-air temperatur	e	-55		125	°C

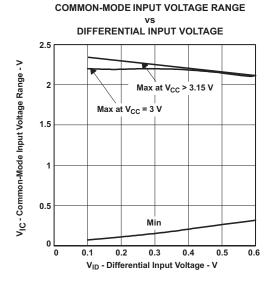


Figure 1.  $V_{IC}$  Versus  $V_{ID}$  and  $V_{CC}$ 



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#### **ELECTRICAL CHARACTERISTICS**

over operating free-air temperature range (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN TYP	<sup>(1)</sup> MAX	UNIT
V <sub>ITH+</sub>	Positive-going differential input voltage threshold	See Figure 2, Table 2, and <sup>(2)</sup>		100	mV
V <sub>ITH-</sub>	Negative-going differential input voltage threshold <sup>(3)</sup>	See Figure 2, Table 2, and <sup>(2)</sup>	-100		mV
V <sub>OH</sub>	High-level output voltage	$I_{OH} = -8 \text{ mA}$	2.4		V
V <sub>OL</sub>	Low-level output voltage	I <sub>OL</sub> = 8 mA		0.4	V
I <sub>CC</sub>	Quantu quimant	Enabled, No load		10 18	~ ^
	Supply current	Disabled	0.2	25 0.5	mA
	lanut current (A. ex D. innute)	V <sub>1</sub> = 0	-2 -'	10 -20	
ų	Input current (A or B inputs)	V <sub>1</sub> = 2.4 V	-1.2	-3	μA
I <sub>I(OFF)</sub>	Power-off input current (A or B inputs)	$V_{CC} = 0,$ $V_{I} = 2.4 V$		6 20	μA
IIH	High-level input current (EN, G, or $\overline{G}$ inputs)	V <sub>IH</sub> = 2 V		10	μA
IIL	Low-level input current (EN, G, or $\overline{G}$ inputs)	V <sub>IL</sub> = 0.8 V		10	μA
l <sub>oz</sub>	High-impedance output current	$V_{O} = 0 \text{ or } V_{CC}$		±12	μA

(1) All typical values are at  $T_A = 25^{\circ}C$  and with  $V_{CC} = 3.3 \text{ V}$ . (2)  $|V_{ITH}| = 200 \text{ mV}$  for operation at  $-55^{\circ}C$ .

The algebraic convention, in which the less-positive (more-negative) limit is designated minimum, is used in this data sheet for the (3) negative-going differential input voltage threshold only.

#### SWITCHING CHARACTERISTICS

over recommended operating conditions (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
t <sub>PLH</sub>	Propagation delay time, low-to-high-level output		1.3	2.3	6	ns
t <sub>PHL</sub>	Propagation delay time, high-to-low-level output		1.4	2.2	6.1	ns
t <sub>sk(o)</sub>	Channel-to-channel output skew <sup>(1)</sup>	C <sub>L</sub> = 10 pF, See Figure 3		0.1		ns
t <sub>r</sub>	Differential output signal rise time (20% to 80%)			0.6		ns
t <sub>f</sub>	Differential output signal fall time (80% to 20%)			0.7		ns
t <sub>PHZ</sub>	Propagation delay time, high-level-to-high-impedance output			6.5	12	ns
t <sub>PLZ</sub>	Propagation delay time, low-level-to-high-impedance output			5.5	12	ns
t <sub>PZH</sub>	Propagation delay time, high-impedance-to-high-level output	See Figure 4		8	12	ns
t <sub>PZL</sub>	Propagation delay time, high-impedance-to-low-level output			3	12	ns

(1)  $t_{sk(o)}$  is the maximum delay time difference between drivers on the same device.



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PARAMETER MEASUREMENT INFORMATION

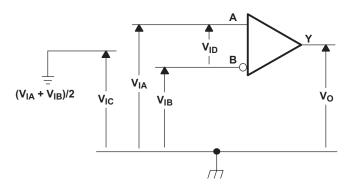


Figure 2. Voltage Definitions

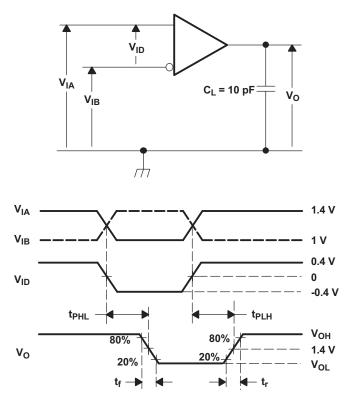
			ona i oos i onnagoo
APPLIED V	OLTAGES <sup>(1)</sup>	RESULTING DIFFERENTIAL INPUT VOLTAGE	RESULTING COMMON- MODE INPUT VOLTAGE
V <sub>IA</sub> (mV)	V <sub>IB</sub> (mV)	V <sub>ID</sub> (mV)	V <sub>IC</sub> (mV)
1.25	1.15	100	1.2
1.15	1.25	-100	1.2
2.4	2.3	100	2.35
2.3	2.4	-100	2.35
0.1	0	100	0.05
0	0.1	-100	0.05
1.5	0.9	600	1.2
0.9	1.5	-600	1.2
2.4	1.8	600	2.1
1.8	2.4	-600	2.1
0.6	0	600	0.3
0	0.6	-600	0.3

(1) These voltages are applied for a minimum of 1.5  $\mu s.$ 





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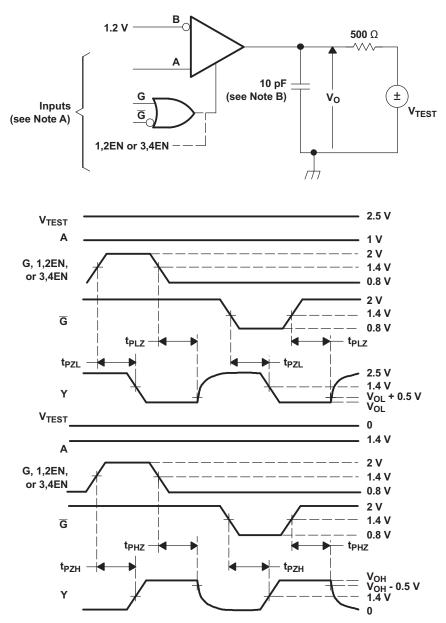


- A. All input pulses are supplied by a generator having the following characteristics:  $t_r$  or  $t_f \le 1$  ns, pulse repetition rate(PRR) = 50 Mpps, pulse width = 10 ±0.2 ns.
- B.  $C_L$  includes instrumentation and fixture capacitance within 6 mm of the D.U.T.





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- A. All input pulses are supplied by a generator having the following characteristics:  $t_r$  or  $t_f \le 1$  ns, pulse repetition rate(PRR) = 0.5 Mpps, pulse width = 500 ± 10 ns.
- B. C<sub>L</sub> includes instrumentation and fixture capacitance within 6 mm of the D.U.T.

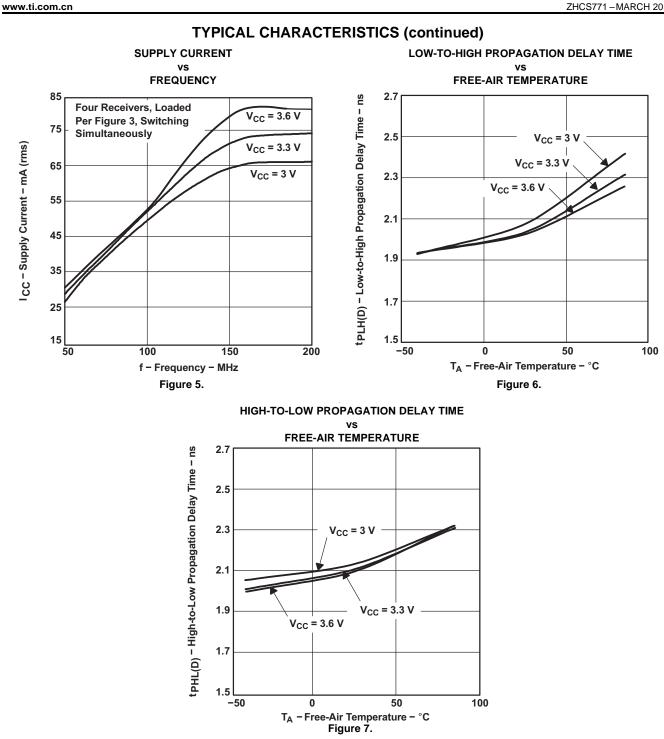
#### Figure 4. Enable- and Disable-Time Test Circuit and Waveforms

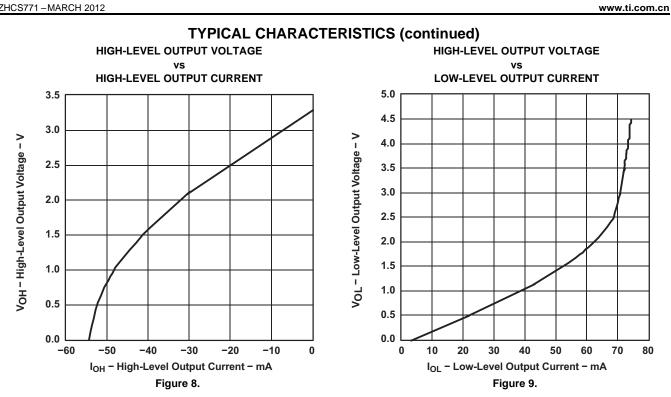
#### **TYPICAL CHARACTERISTICS**



## SN55LVDS32-SP









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### **APPLICATION INFORMATION**

#### EQUIPMENT

- Hewlett Packard HP6624A DC power supply
- Tektronix TDS7404 Real Time Scope
- Agilent ParBERT E4832A

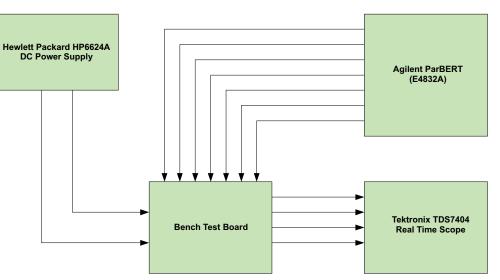
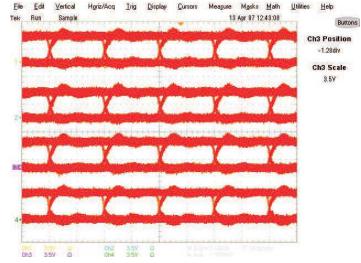


Figure 10. Equipment Setup



All Rx running at 100 Mbps; Channel 1: 1Y, Channel 2: 2Y; Channel 3: 3Y; Channel 4: 4Y

### Figure 11. Typical Eye Patterns SN55LVDS32: (T = 25°C; $V_{CC}$ = 3.6 V; PRBS = 2<sup>23-1</sup>)

#### USING AN LVDS RECEIVER WITH RS-422 DATA

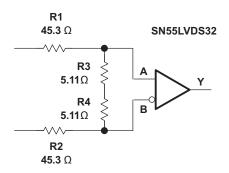
Receipt of data from a TIA/EIA-422 line driver can be accomplished using a TIA/EIA-644 line receiver with the addition of an attenuator circuit. This technique gives the user a high-speed and low-power 422 receiver.

If the ground noise between the transmitter and receiver is not a concern (less than  $\pm 1$  V), the answer can be as simple as shown in Figure 12. A resistor divider circuit in front of the LVDS receiver attenuates the 422 differential signal to LVDS levels.



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The resistors present a total differential load of 100  $\Omega$  to match the characteristic impedance of the transmission line and to reduce the signal 10:1. The maximum 422 differential output signal, or 6 V, is reduced to 600 mV. The high input impedance of the LVDS receiver prevents input bias offsets and maintains a greater than 200-mV differential input voltage threshold at the inputs to the divider. This circuit is used in front of each LVDS channel that also receives 422 signals.

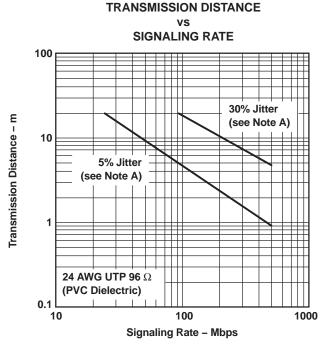


NOTE: The components used were standard values. (1) R1, R2 = NRC12F45R3TR, NIC components, 45.3 Ω, 1/8 W, 1%, 1206 package (2) R3, R4 = NRC12F5R11TR, NIC components, 5.11 Ω, 1/8 W, 1%, 1206 package (3) The resistor values do not need to be 1% tolerance. However, it can be difficult locating a supplier of resistors having values less than 100 Ω in stock and readily available. The user may find other suppliers with comparable parts having tolerances of 5% or even 10%. These parts are adequate for use in this circuit.

#### Figure 12. RS-422 Data Input to an LVDS Receiver Under Low Ground-Noise Conditions

If ground noise between the RS-422 driver and LVDS receiver is a concern, the common-mode voltage must be attenuated. The circuit must then be modified to connect the node between R3 and R4 to the LVDS receiver ground. This modification to the circuit increases the common-mode voltage from  $\pm 1$  V to greater than  $\pm 4.5$  V.

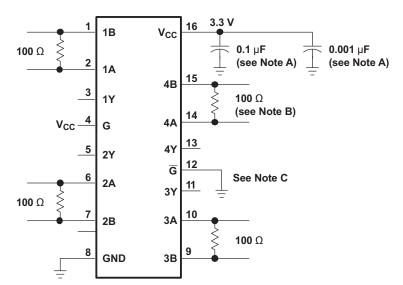
The devices are generally used as building blocks for high-speed point-to-point data transmission where ground differences are less than 1 V. Devices can interoperate with RS-422, PECL, and IEEE-P1596. Drivers/receivers approach ECL speeds without the power and dual-supply requirements.



A. This parameter is the percentage of distortion of the unit interval (UI) with a pseudorandom data pattern.

#### Figure 13. Typical Transmission Distance Versus Signaling Rate



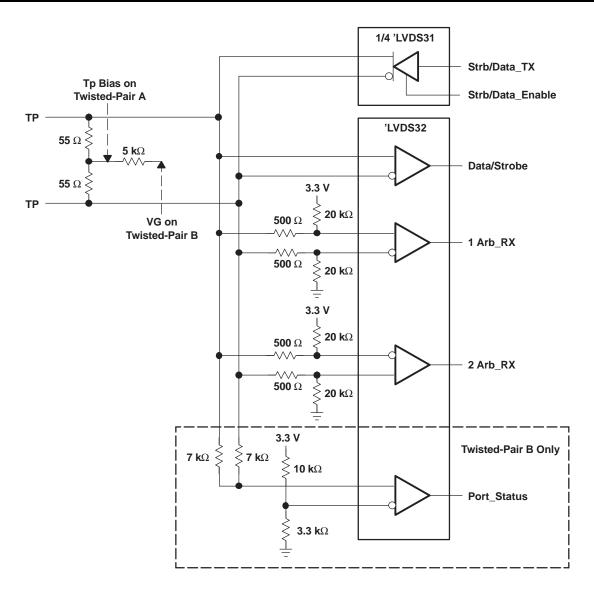


- A. Place a 0.1-μF and a 0.001-μF Z5U ceramic, mica, or polystyrene dielectric, 0805 size, chip capacitor between VCC and the ground plane. The capacitors should be located as close as possible to the device terminals.
- B. The termination resistance value should match the nominal characteristic impedance of the transmission media with  $\pm 10\%$ .
- C. Unused enable inputs should be tied to  $V_{\mbox{\scriptsize CC}}$  or GND as appropriate.

Figure 14. Typical Application Circuit Schematic

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NOTES: A. Resistors are leadless, thick film (0603), 5% tolerance.

- B. Decoupling capacitance is not shown, but recommended.
- C.  $V_{CC}$  is 3 V to 3.6 V.
- D. The differential output voltage of the 'LVDS31 can exceed that specified by IEEE1394.

#### Figure 15. 100-Mbps IEEE 1394 Transceiver

#### FAIL-SAFE

One of the most common problems with differential signaling applications is how the system responds when no differential voltage is present on the signal pair. The LVDS receiver is like most differential line receivers in that its output logic state can be indeterminate when the differential input voltage is between -100 mV and100 mV if it is within its recommended input common-mode voltage range. However, TI LVDS receivers handle the open-input circuit situation differently.

Open-input circuit means that there is little or no input current to the receiver from the data line itself. This could be when the driver is in a high-impedance state or the cable is disconnected. When this occurs, the LVDS receiver pulls each line of the signal pair to near  $V_{CC}$  through 300-k $\Omega$  resistors (see Figure 16). The fail-safe feature uses an AND gate with input voltage thresholds at about 2.3 V to detect this condition and force the output to a high level, regardless of the differential input voltage.



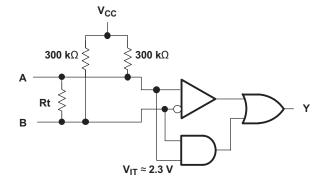
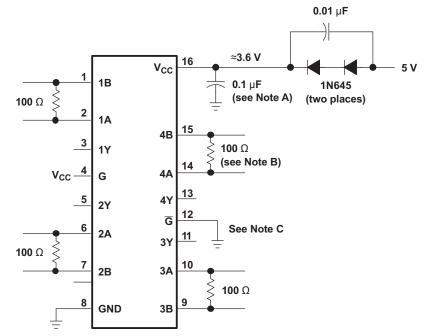


Figure 16. Open-Circuit Fail-Safe of LVDS Receiver

It is only under these conditions that the output of the receiver is valid with less than a 100-mV differential input voltage magnitude. The presence of the termination resistor, Rt, does not affect the fail-safe function as long as it is connected as shown in Figure 16. Other termination circuits may allow a dc current to ground that could defeat the pullup currents from the receiver and the fail-safe feature.



- A. Place a 0.1-µF Z5U ceramic, mica, or polystyrene dielectric, 0805 size, chip capacitor between V<sub>CC</sub> and the ground plane. The capacitor should be located as close as possible to the device terminals.
- B. The termination resistance value should match the nominal characteristic impedance of the transmission media with  $\pm 10\%$ .
- C. Unused enable inputs should be tied to V<sub>CC</sub> or GND, as appropriate.

#### Figure 17. Operation With 5-V Supply

#### **COLD SPARING**

Systems using cold sparing have a redundant device electrically connected without power supplied. To support this configuration, the spare must present a high-input impedance to the system so that it does not draw appreciable power. In cold sparing, voltage may be applied to an I/O before and during power up of a device. When the device is powered off, V<sub>CC</sub> must be clamped to ground and the I/O voltages applied must be within the specified recommended operating conditions.

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# RELATED INFORMATION

IBIS modeling is available for this device. Contact the local TI sales office or the TI Web site at www.ti.com for more information.

For more application guidelines, see the following documents:

- Low-Voltage Differential Signaling Design Notes (SLLA014)
- Interface Circuits for TIA/EIA-644 (LVDS) (SLLA038)
- Reducing EMI With LVDS (SLLA030)
- Slew Rate Control of LVDS Circuits (SLLA034)
- Using an LVDS Receiver With RS-422 Data (SLLA031)



#### PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead finish/ Ball material (6)	MSL Peak Temp (3)	Op Temp (°C)	Device Marking (4/5)	Samples
5962-9762201VFA	ACTIVE	CFP	W	16	25	Non-RoHS & Green	SNPB	N / A for Pkg Type	-55 to 125	5962-9762201VF A SNV55LVDS32W	Samples

<sup>(1)</sup> The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

**NRND:** Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

<sup>(2)</sup> RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

**RoHS Exempt:** TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

<sup>(3)</sup> MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

<sup>(4)</sup> There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

<sup>(5)</sup> Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

<sup>(6)</sup> Lead finish/Ball material - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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#### OTHER QUALIFIED VERSIONS OF SN55LVDS32-SP :

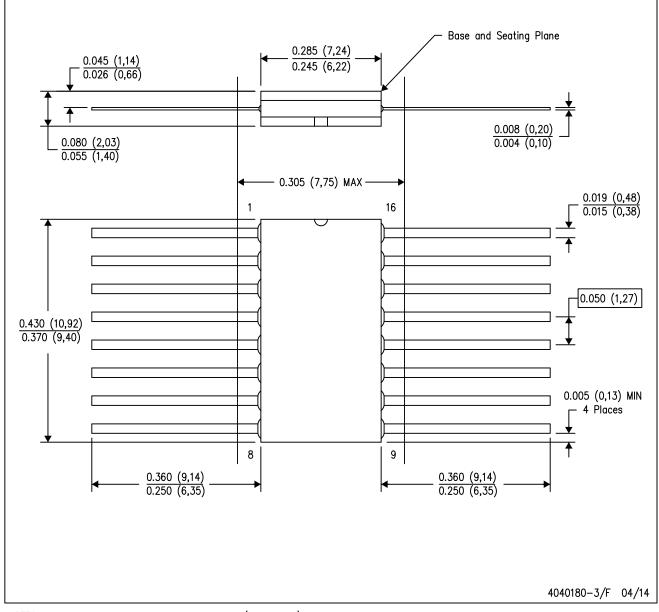
• Catalog : SN55LVDS32

NOTE: Qualified Version Definitions:

• Catalog - TI's standard catalog product

W (R-GDFP-F16)

CERAMIC DUAL FLATPACK



- NOTES: A. All linear dimensions are in inches (millimeters).
  - B. This drawing is subject to change without notice.
  - C. This package can be hermetically sealed with a ceramic lid using glass frit.
  - D. Index point is provided on cap for terminal identification only.
  - E. Falls within MIL STD 1835 GDFP2-F16



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